

INFORMAZIONI PERSONALI **Susto Gian Antonio**

Sesso | Data di nascita | Nazionalità

ESPERIENZA
PROFESSIONALE

- 01/08/2016–alla data attuale **Ricercatore Universitario a Tempo Determinato di Tipo A**
Università degli Studi di Padova, Padova (Italia)
- Ricercatore presso il Dipartimento di Ingegneria dell'Informazione
- Docente di Controlli Automatici per la Laurea Triennale in Ingegneria Gestionale
- 01/09/2014–31/07/2016 **Assegnista di Ricerca Senior**
Università degli Studi di Padova, Padova (Italia)
- 01/09/2013–31/08/2014 **Assegnista di Ricerca**
Università degli Studi di Padova, Padova (Italia)
- 01/09/2012–31/08/2013 **Post-Doctoral Researcher**
National University of Ireland, Maynooth, Maynooth, Irlanda
- 01/03/2011–08/08/2011 **Research Engineer**
Infineon Technologies AG, Villach (Austria)

ISTRUZIONE E FORMAZIONE

- 01/01/2010–31/12/2012 **Dottore di Ricerca in Ingegneria dell'Informazione**
Univesità degli Studi di Padova, Padova (Italia)
Tesi dal titolo: 'STATISTICAL METHODS FOR SEMICONDUCTOR MANUFACTURING'
- 01/10/2006–30/04/2009 **Laura Specialistica in Ingegneria dell'Automazione**
Università degli Studi di Padova, Padova (Italia)
- 01/10/2003–31/07/2006 **Laurea Triennale in Ingegneria dell'Automazione**
Università degli Studi di Padova, Padova (Italia)

COMPETENZE PERSONALI

Lingua madre italiano

Lingue straniere	COMPRESIONE		PARLATO		PRODUZIONE SCRITTA
	Ascolto	Lettura	Interazione	Produzione orale	
inglese	C2	C2	C2	C2	C2

Livelli: A1 e A2: Utente base - B1 e B2: Utente autonomo - C1 e C2: Utente avanzato
Quadro Comune Europeo di Riferimento delle Lingue

ULTERIORI INFORMAZIONI

Nato a Monselice il 07/04/1984
Codice Fiscale: SSTGNT84D07F382F

- Publicazioni in ambito Big Data, Industria 4.0 e Internet delle Cose
- N. Normani, A. Urru, L. Abraham, M. Walsh, S. Tedesco, A. Cenedese, G.A. Susto, B. O'Flynn. **A Machine Learning Approach for Gesture Recognition with a Lensless Smart Sensor System.** *15th International Conference on Wearable and Implantable Body Sensor Networks - 2018*
- M. Maggipinto, C. Masiero, A. Beghi, G.A. Susto. **A Convolutional Autoencoder Approach for Feature Extraction in Virtual Metrology.** *Procedia Manufacturing, 28th International Conference on Flexible Automation and Intelligent Manufacturing, 2018*
- G.A. Susto, M. Maggipinto, F. Zocco, S. McLoone. **A Dynamic Sampling Approach for Cost Reduction in Semiconductor Manufacturing.** *Procedia Manufacturing, 28th International Conference on Flexible Automation and Intelligent Manufacturing, 2018*
- G.A. Susto, A. Schirru, S. Pampuri, A. Beghi, G. De nicolao. **A Hidden-Gamma Model-Based Filtering and Prediction Approach for Monotonic Health Factors in Manufacturing.** *Control Engineering Practice*, vol. 74pp. 84-94, 2018
- S. McLoone, A.B. Johnston, G.A. Susto. **A Methodology for Efficient Dynamic Spatial Sampling and Reconstruction of Wafer Profiles.** *IEEE Transactions on Automation Science and Engineering*, 2018
- G.A. Susto, M. Maggipinto, G. Zannon, F. Altinier, E. Pesavento, A. Beghi. **Machine Learning-based Laundry Weight Estimation for Vertical Axis Washing Machines.** *European Control Conference (ECC2018)*, 2018
- S. McLoone, F. Zocco, M. Maggipinto, G.A. Susto. **On Optimising Spatial Sampling Plans for Wafer Profile Reconstruction.** *3rd IFAC Conference on Embedded Systems, Computational Intelligence and Telematics in Control*, 2018
- G.A. Susto. **A Dynamic Sampling Strategy based on Confidence Level of Virtual Metrology Predictions.** *IEEE/SEMI Advanced Semiconductor Manufacturing Conference*, pp. 78-83, 2017
- M. Terzi, A. Cenedese, G.A. Susto. **A multivariate symbolic approach to activity recognition for wearable applications.** *IFAC World Congress 2017*, pp. 16435-16440, 2017
- G.A. Susto, M. Terzi, A. Beghi. **Anomaly Detection Approaches for Semiconductor Manufacturing.** *Procedia Manufacturing, 27th International Conference on Flexible Automation and Intelligent Manufacturing*, vol. 11pp. 2018-2024, 2017
- G.A. Susto, A. Beghi, S. McLoone. **Anomaly Detection through on-line Isolation Forest: an Application to Plasma Etching.** *IEEE/SEMI Advanced Semiconductor Manufacturing Conference*, 2017
- M. Terzi, C. Masiero, A. Beghi, M. Maggipinto, G.A. Susto. **Deep Learning for Virtual Metrology: Modeling with Optical Emission Spectroscopy Data.** *IEEE 3rd International Forum on Research and Technologies for Society and Industry (RTSI)*, 2017
- G.A. Susto, A. Cenedese, M. Terzi. **Big Data Application in Power Systems - Ch. 2.5. Time Series**

Classification Methods: Review and Applications to Power Systems Data. 2017

A. Cenedese, G.A. Susto, M. Terzi. **A Parsimonious Approach for Activity Recognition with Wearable Devices: an Application to Cross-country Skiing**. *European Control Conference 2016 (ECC'16)*, pp. 2541-2546, 2016

A. Cenedese, L. Minetto, G.A. Susto, M. Terzi. **A Symbolic Approach to Human Activity Recognition**. *5th International Workshop on Symbiotic Interaction*, 2016

G.A. Susto, A. Beghi. **Dealing with Time-Series Data in Predictive Maintenance Problems**. *Emerging Technologies and Factory Automation*, 2016

A. Cenedese, L. Minetto, G.A. Susto, M. Terzi. **Human Activity Recognition with Wearable Devices: A Symbolic Approach**. *PsychNology*, vol. 14(2-3), pp. 99-115, 2016

G.A. Susto, A. Schirru, S. Pampuri, S. McLoone. **Supervised Aggregative Feature Extraction for Big Data Time Series Regression**. *IEEE Transactions on Industrial Informatics*, vol. 12pp. 1243 - 1252, 2016

A. Cenedese, G.A. Susto, G. Belgioioso, G.I. Cirillo, F. Fraccaroli. **Home Automation Oriented Gesture Classification From Inertial Measurements**. *IEEE Transactions on Automation Science and Engineering*, vol. 12(4), pp. 1200--1210, 2015

G.A. Susto, A. Schirru, S. Pampuri, S. McLoone, A. Beghi. **Machine Learning for Predictive Maintenance: a Multiple Classifiers Approach**. *IEEE Transactions on Industrial Informatics*, vol. 11(3), pp. 812 - 820, 2015

G.A. Susto, S. Pampuri, A. Schirru, A. Beghi, G. De nicolao. **Multi-Step Virtual Metrology for Semiconductor Manufacturing: a Multilevel and Regularization Methods-based Approach**. *Computers & Operations Research*, vol. 53pp. 328--337, 2015

G.A. Susto, S. McLoone. **Slow Release Drug Dissolution Profile Prediction in Pharmaceutical Manufacturing: a Multivariate and Machine Learning Approach**. *11th IEEE Conference on Automation Science and Engineering*, pp. 1218-1223, 2015

G. Belgioioso, A. Cenedese, G.I. Cirillo, F. Fraccaroli, G.A. Susto. **A Machine Learning based Approach for Gesture Recognition from Inertial Measurements**. *IEEE 53rd Conference on Decision and Control*, pp. 4899--4904, 2014

A. Beghi, L. Cecchinato, C. Corazzol, M. Rampazzo, F. Simmini, G.A. Susto. **A One-Class SVM Based Tool for Machine Learning Novelty Detection in HVAC Chiller Systems**. *19th World Congress of the International Federation of Automatic Control*, pp. 1953-1958, 2014

G.A. Susto, S. Pampuri, M. Zanon, A.B. Johnston, P.G. O'Hara, S. McLoone. **An Adaptive Machine Learning Decision System for Flexible Predictive Maintenance**. *Conference on Automation Science and Engineering*, pp. 806-811, 2014

S. Pampuri, G.A. Susto, J. Wan, A.B. Johnston, P.G. O'Hara, S. McLoone. **Insight Extraction for Semiconductor Manufacturing Processes**. *Conference on Automation Science and Engineering*, pp. 786 - 791, 2014

- M. Zanon, G.A. Susto, S. McLoone. **Root Cause Analysis by a Combined Sparse Classification and Monte Carlo Approach.** *19th World Congress of the International Federation of Automatic Control*, pp. 1947-1952, 2014
- G.A. Susto, A. Schirru, S. Pampuri, D. Pagano, S. McLoone, A. Beghi. **A Predictive Maintenance System for Integral Type Faults based on Support Vector Machines: an Application to Ion Implantation.** *Automation Science and Engineering (CASE), 2013 IEEE International Conference on*, 2013
- G.A. Susto, A. Beghi. **A virtual metrology system based on least angle regression and statistical clustering.** *Applied Stochastic Models in Business and Industry*, vol. 29(4), pp. 362-376, 2013
- G.A. Susto, S. McLoone, A. Schirru, S. Pampuri, D. Pagano, A. Beghi. **Prediction of Integral Type Failures in Semiconductor Manufacturing through Classification Methods.** *18-th IEEE Conference on Emerging Technologies and Factory Automation*, 2013
- G.A. Susto, A.B. Johnston, P.G. O'Hara, S. McLoone. **Virtual Metrology Enabled Early Stage Prediction for Enhanced Control of Multi-stage Fabrication Processes.** *Automation Science and Engineering (CASE), 2013 IEEE International Conference on*, 2013
- G.A. Susto, A. Schirru, S. Pampuri, A. Beghi. **A Predictive Maintenance System based on Regularization Methods for Ion-Implantation.** *23rd IEEE/SEMI Advanced Semiconductor Manufacturing Conference*, pp. 175-180, 2012
- G.A. Susto, A. Beghi, C. De luca. **A Predictive Maintenance System for Epitaxy Processes based on Filtering and Prediction Techniques.** *IEEE Transactions on Semiconductor Manufacturing*, vol. 25pp. 638 - 649, 2012
- G.A. Susto, A. Beghi. **An Information Theory-based Approach to Data Clustering for Virtual Metrology and Soft Sensors.** *3rd International conference on CIRCUITS, SYSTEMS, CONTROL, SIGNALS*, pp. 198--203, 2012
- G.A. Susto, A. Schirru, S. Pampuri, G. De nicolao, A. Beghi. **An Information-Theory and Virtual Metrology-based approach to Run-to-Run Semiconductor Manufacturing Control.** *Automation Science and Engineering (CASE), 2012 IEEE International Conference on*, pp. 358 -363, 2012
- G.A. Susto, S. Pampuri, A. Schirru, G. De nicolao, S. McLoone, A. Beghi. **Automatic Control and Machine Learning for Semiconductor Manufacturing: Review and Challenges.** *10th European Workshop on Advanced Control and Diagnosis*, 2012
- A. Schirru, G.A. Susto, S. Pampuri, S. McLoone. **Learning from Time Series: Supervised Aggregative Feature Extraction.** *51st IEEE Conference on Decision and Control*, pp. 5254--5259, 2012
- G.A. Susto, A. Beghi. **Least Angle Regression for Semiconductor Manufacturing Modeling.** *Control Applications (CCA), 2012 IEEE International Conference on*, pp. 658--663, 2012
- S. Pampuri, A. Schirru, G.A. Susto, G. De nicolao, A. Beghi, C. De luca. **Multistep Virtual Metrology Approaches for Semiconductor Manufacturing Processes.** *Automation Science and Engineering (CASE), 2012 IEEE International Conference on*, pp. 91 -- 96, 2012

G.A. Susto, S. Pampuri, A. Schirru, A. Beghi. **Optimal Tuning of Epitaxy Pyrometers.** *23rd IEEE/SEMI Advanced Semiconductor Manufacturing Conference*, pp. 294-299, 2012

G.A. Susto, A. Beghi, C. De luca. **A Predictive Maintenance System for Silicon Epitaxial Deposition.** *Proceeding of 7th IEEE International Conference on Automation Science and Engineering*, pp. 262-267, 2011

G.A. Susto, A. Beghi, C. De luca. **A Virtual Metrology System for Predicting CVD Thickness with Equipment Variables and Qualitative Clustering.** *Proceeding of 16th IEEE International Conference on Emerging Technologies and Factory Automation*, pp. 1-4, 2011

Il sottoscritto, ai sensi degli artt. 46 e 47 del DPR 445/2000, conferma che quanto sopra dichiarato corrisponde a verità. Inoltre, ai sensi dell'art. 76 del DPR 445/2000, dichiara di essere consapevole del fatto che chiunque rilascia dichiarazioni mendaci, forma atti falsi o ne fa uso nei casi previsti è punito dal codice penale e/o dalle leggi speciali in materia.

Trattamento dei dati personali Autorizzo il trattamento dei miei dati personali ai sensi del Decreto Legislativo 30 giugno 2003, n. 196 "Codice in materia di protezione dei dati personali."